



Characterizing x-ray mirrors in reciprocal space

*Preliminary results from the NIST
X-ray Optics Evaluation Double-Crystal Diffractometer*

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Introduction

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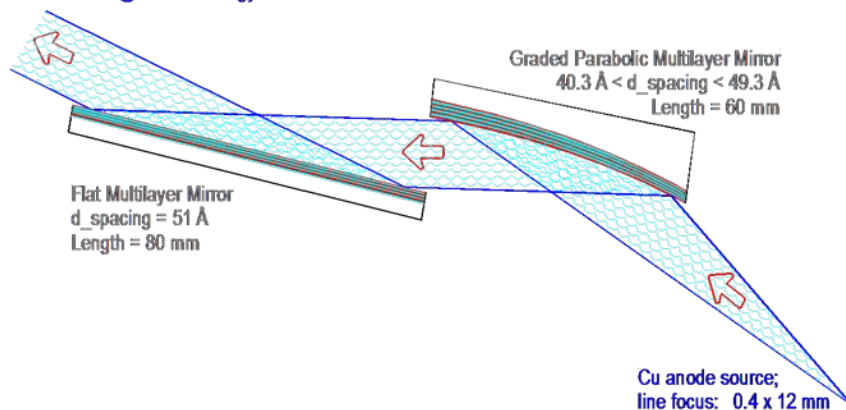
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Old NIST PBPD instrument

- Deslattes et al. demonstrated the usefulness of PGM optics for high-accuracy PD lattice parameter measurement
- Certification of SRMs 640c and 660a
- Difficulties in modeling due to unknown beam character

Cross section of parallel x-rays: about 0.7×15 mm
Flux = 5 GHz @ 2 kW. Energy window = 40 eV



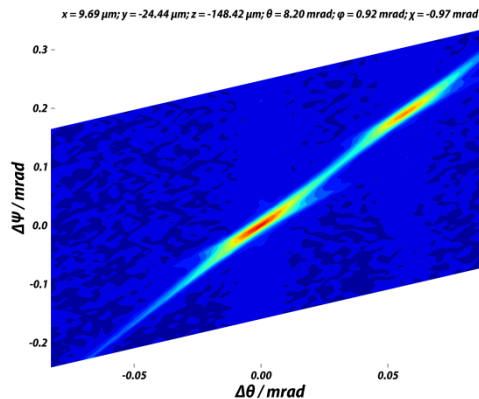
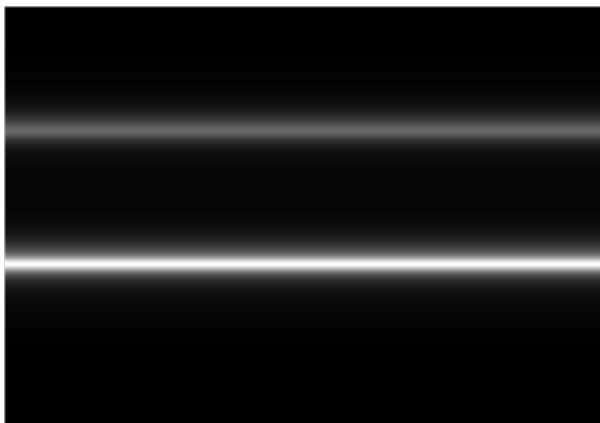
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Character of parabolic graded multilayer mirrors in reciprocal space

- Character of mirror source is very different from bare anodes
 - **PGMs provide high reflectivity by diffraction**
 - **Diffraction implies dispersion**
- Wavelength/divergence character needed for data analysis



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Questions for using PGMs for x-ray metrology applications

- Many questions
 - **When is a PGM aligned “well”?**
 - **What do you need to do to align a PGM?**
 - Typical approach is purely intensity based
 - Does maximizing intensity uniquely specify wavelength/divergence character?
 - **How sensitive are PGMs to drift?**
 - Stability
 - Cold alignment
- The question: What is the wavelength/divergence character of the beam produced by PGM as alignment is varied?

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The question for using PGMs for x-ray metrology

- What is the wavelength/divergence character of the beam produced by PGM as alignment is varied?
- Previous studies
 - **Most work on graded multilayer optics has concerned spatial characteristics (usually for a single wavelength)**
 - **Toraya and Hibino (2000) performed very useful single-crystal study of PGMs**
- How to answer the question?
 - **An instrument that can position a PGM in its six DOF and measure its wavelength/divergence character**
 - **Experiment designs to explore eight-dimensional space**

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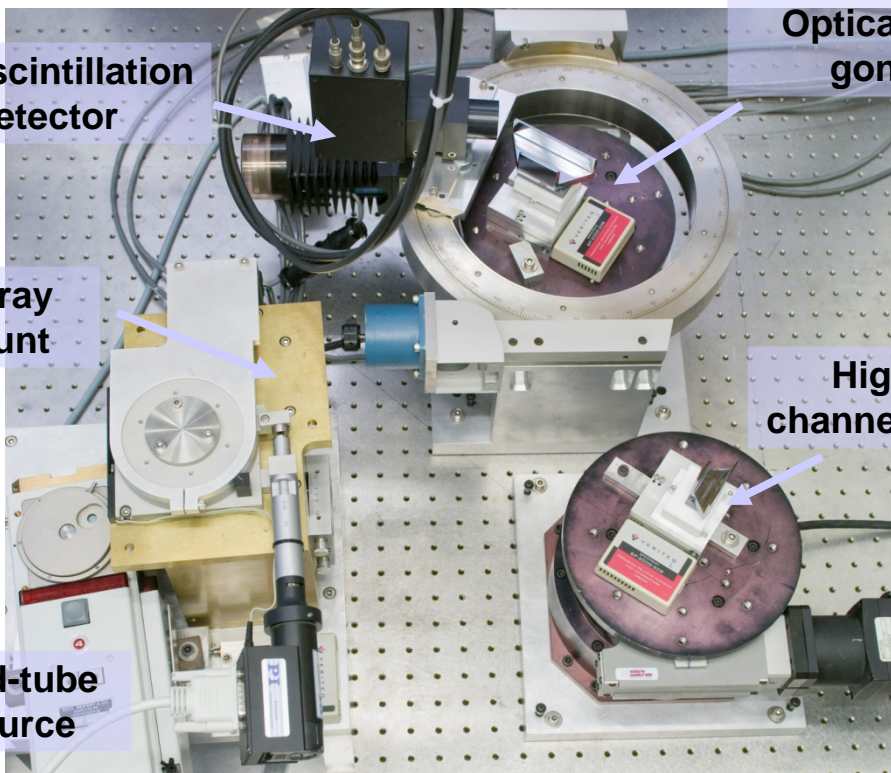
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The NIST X-ray Optics Evaluation Double-Crystal Diffractometer **Instrument**



XOEDCD overview picture



HDR scintillation detector

Optically encoded goniometers

Six-axis x-ray mirror mount

High-resolution channel-cut Si crystals

Cu sealed-tube x-ray source

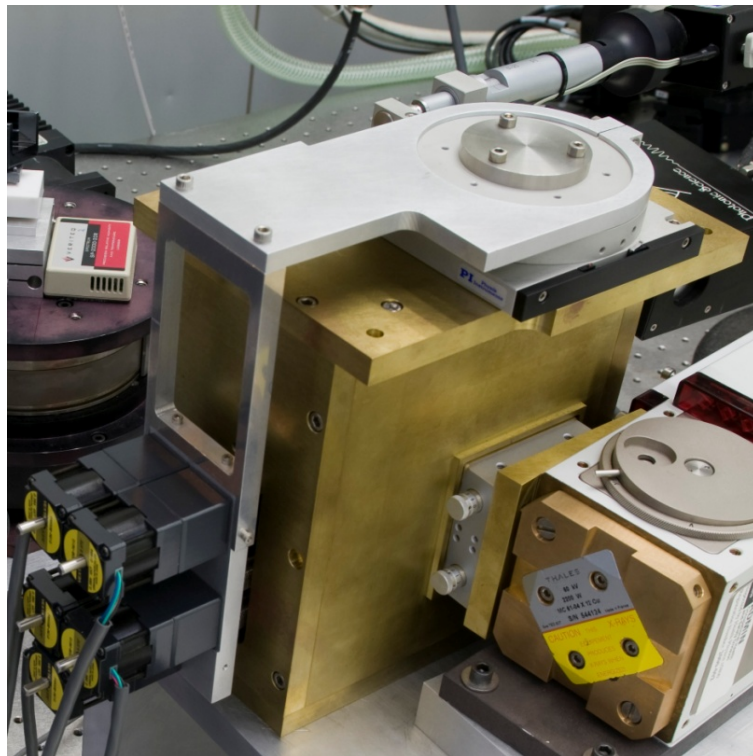
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Six-axis mirror mount

- Stepper motor driven New Focus five-axis kinematic alignment stage
- Servo driven Physik Instrumente tangent arm
- Accuracy studied by autocollimator measurements



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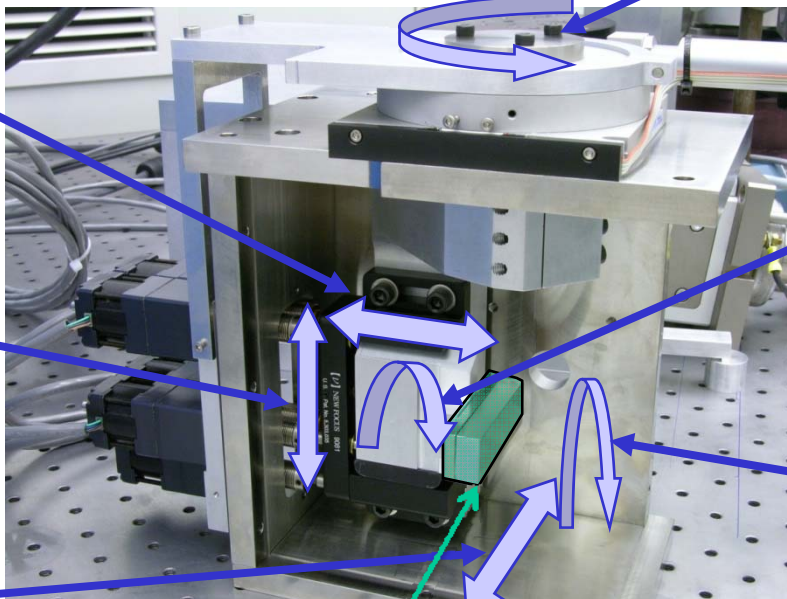
Six-axis stage directions of motion

θ

z

y

x



X

Tilt

ϕ

Azimuth

X-ray mirror

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Toraya and Hibino diagram

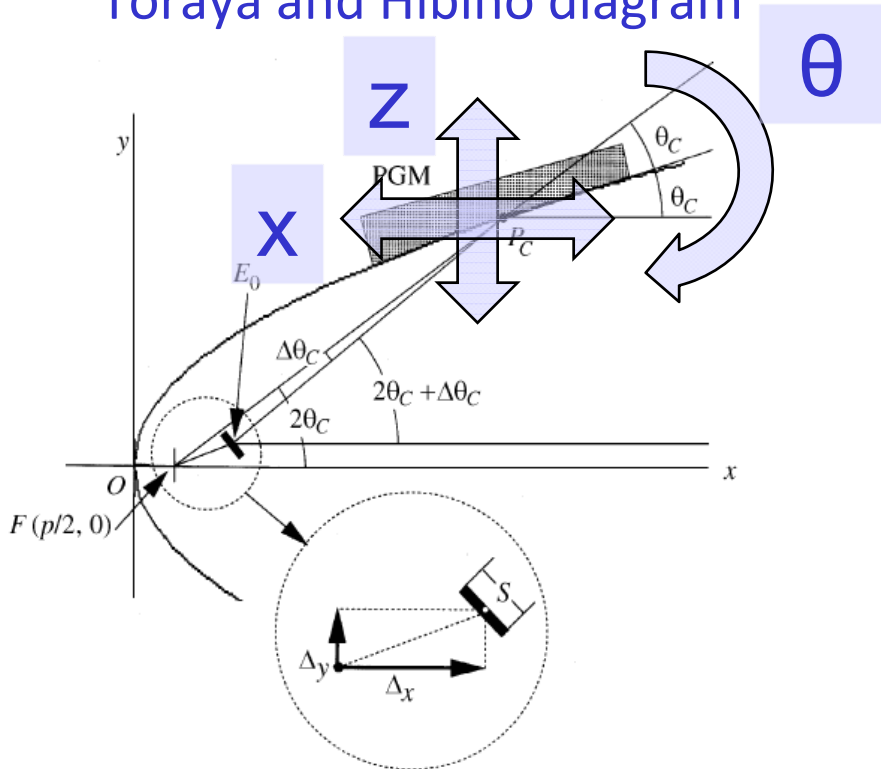


Figure 1

Geometrical arrangement of the X-ray focus and the parabolic graded multilayer (PGM).

from Toraya and Hibino (2000), 1318

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Approaches to exploring the six-dimensional mirror
position space

Experiment Design

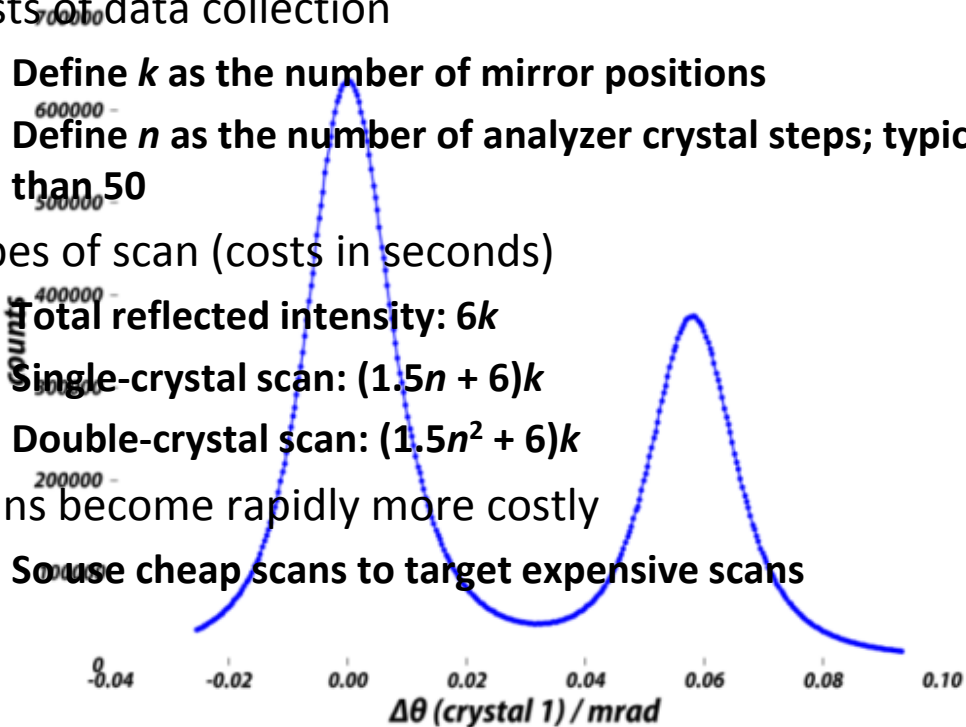
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Approach to data collection

- Costs of data collection
 - Define k as the number of mirror positions
 - Define n as the number of analyzer crystal steps; typically greater than 50
- Types of scan (costs in seconds)
 - Total reflected intensity: $6k$
 - Single-crystal scan: $(1.5n + 6)k$
 - Double-crystal scan: $(1.5n^2 + 6)k$
- Scans become rapidly more costly
 - So use cheap scans to target expensive scans





Experiment Designs

- Single-axis variation
 - If effects of axes are completely uncorrelated, find maximum of intensity and scan each axis separately
 - But if there's correlation, this produces wrong estimates of effects
- Factorial and fractional factorial designs
 - Effective, easy to interpret conventional statistical designs
 - Typically only used for 2, occasionally 3 levels
- Monte Carlo and Quasi-Monte Carlo methods

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Monte Carlo and Quasi-Monte Carlo

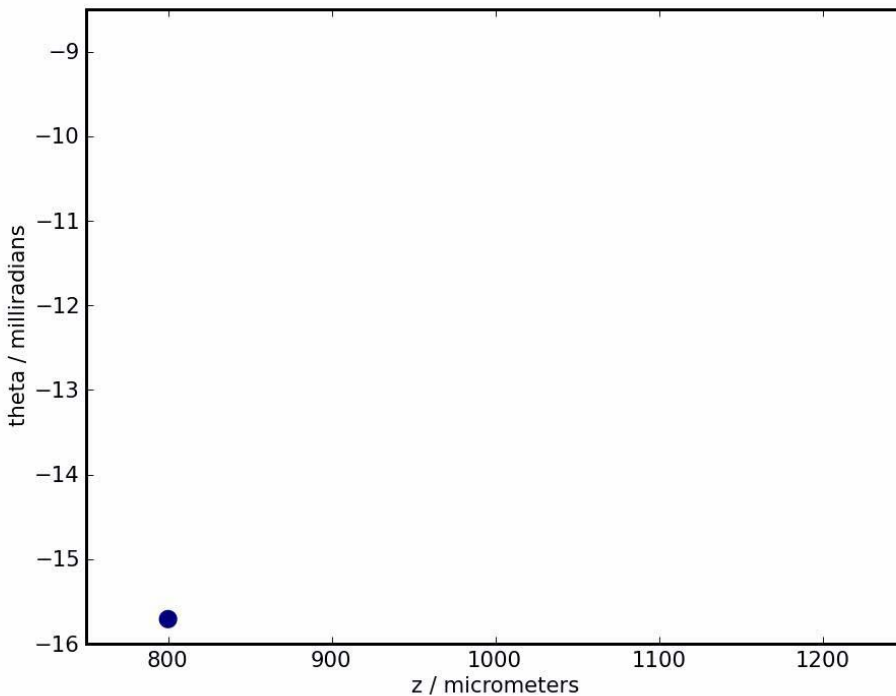
- Monte Carlo
 - Random sampling of space
 - Easy method: just pick uniformly distributed random deviates
- Quasi-Monte Carlo
 - Low-discrepancy random numbers: fills the space uniformly
 - Sequential: can terminate at any time and still have a 'fair' sample

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Theta angle versus z position scatter plot movie



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Results from Quasi-Monte Carlo study of the variation of total reflected intensity with mirror position

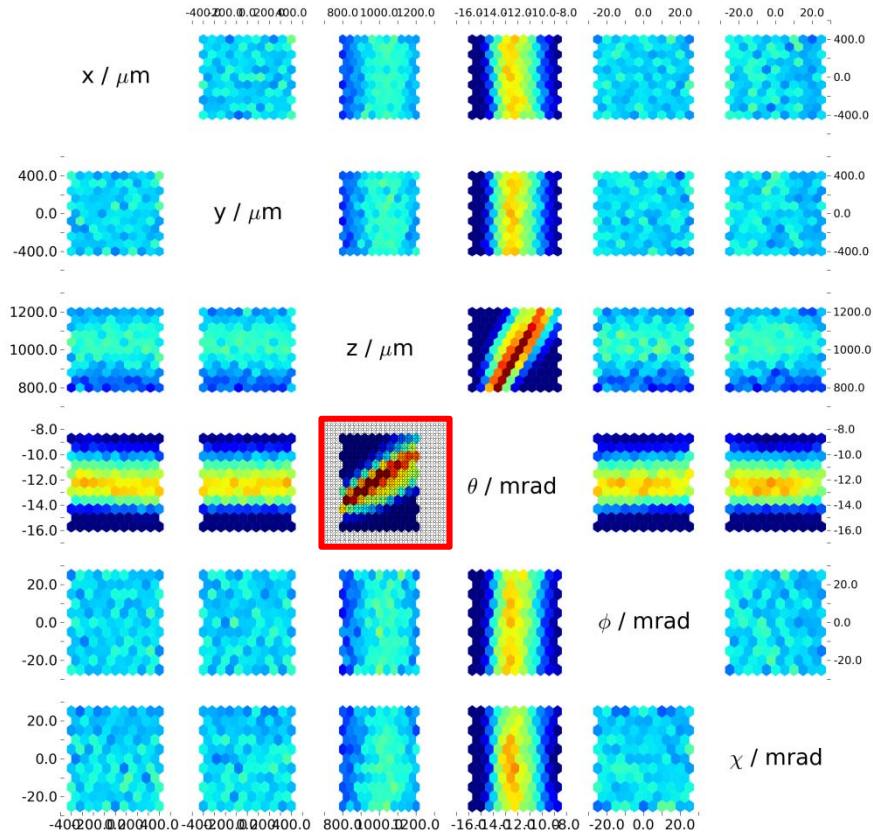
Data

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Two-dimensional hexagonal bin plots



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Toraya and Hibino: Theta angle and z position

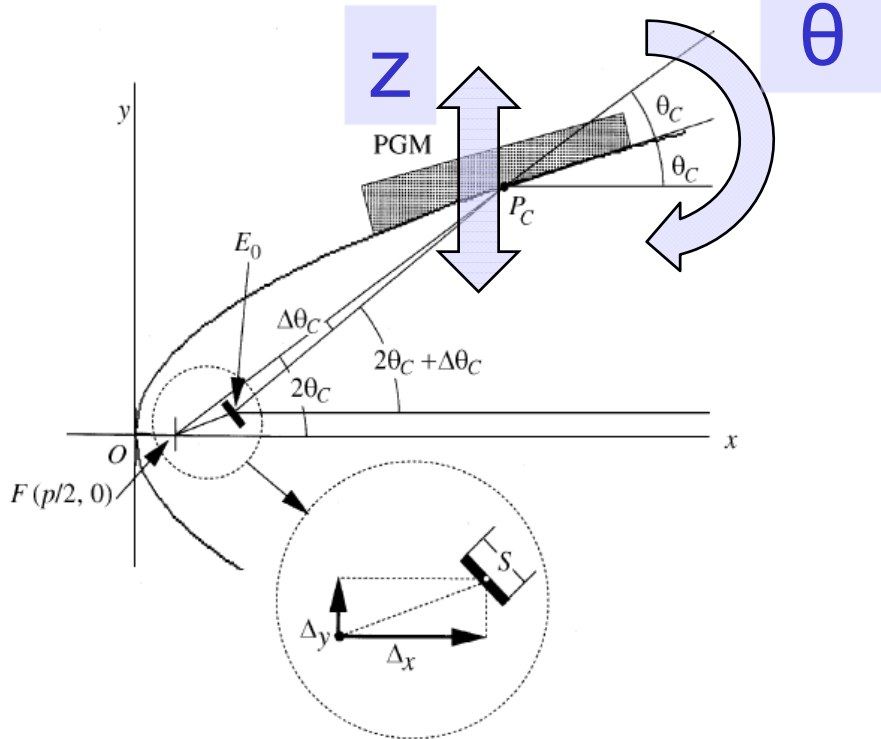


Figure 1

Geometrical arrangement of the X-ray focus and the parabolic graded multilayer (PGM).

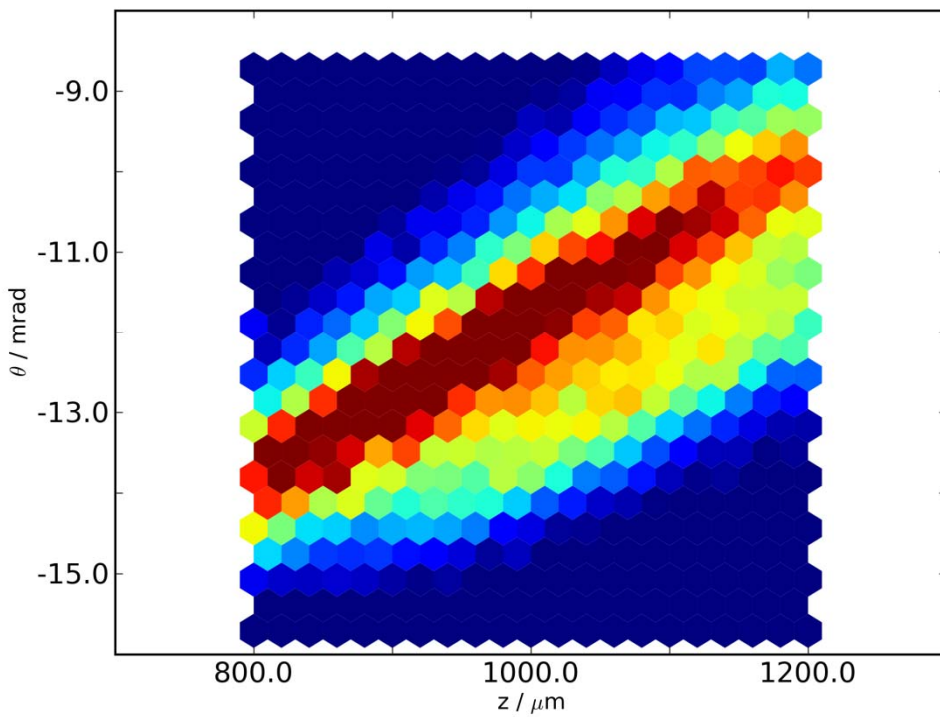
from Toraya and Hibino (2000), 1318

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Theta angle versus z position

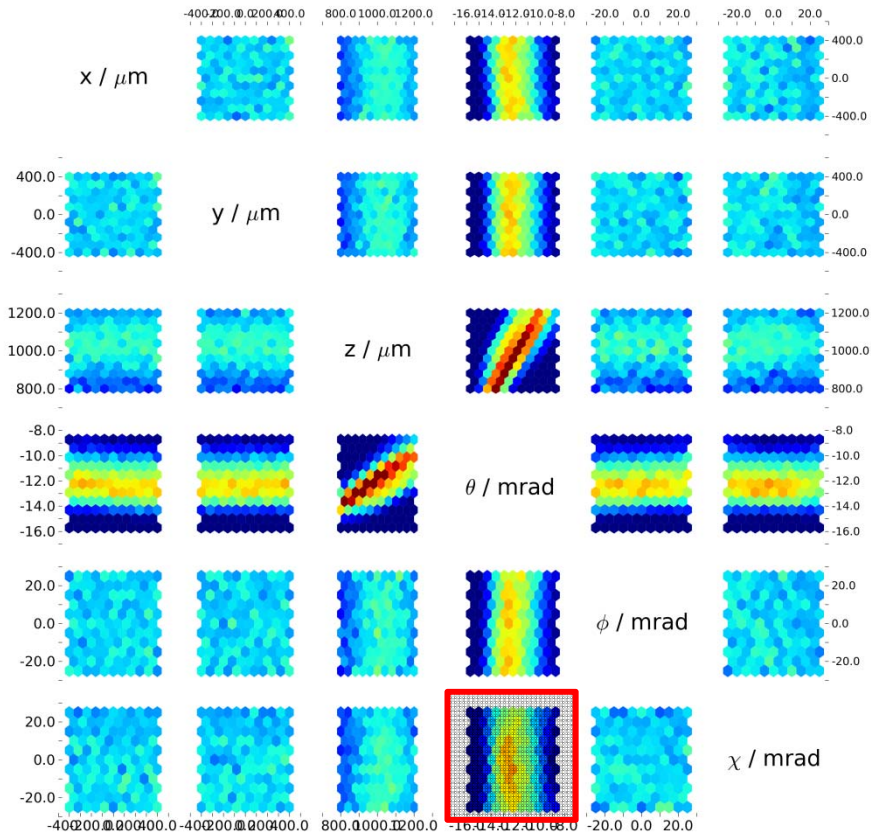


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Two-dimensional hexagonal bin plots

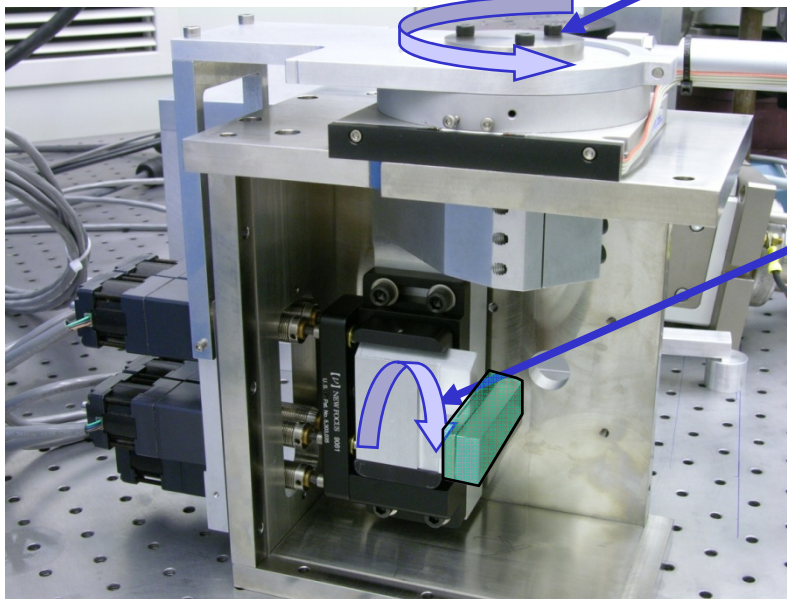


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Six-axis stage directions of motion: theta angle and chi angle



θ

X

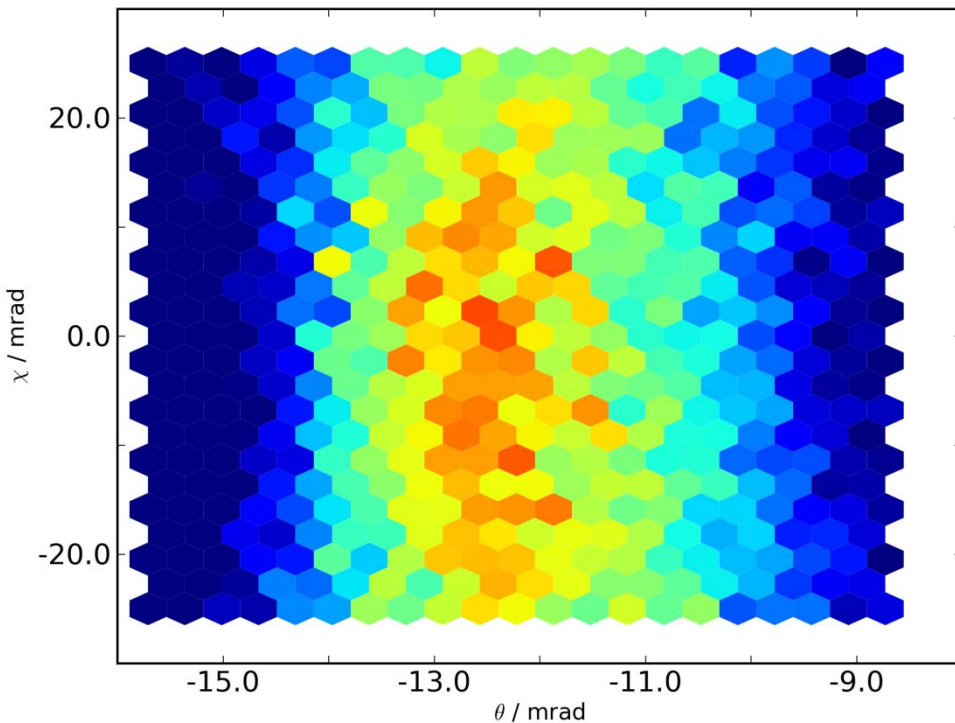
Tilt

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Chi angle versus theta angle

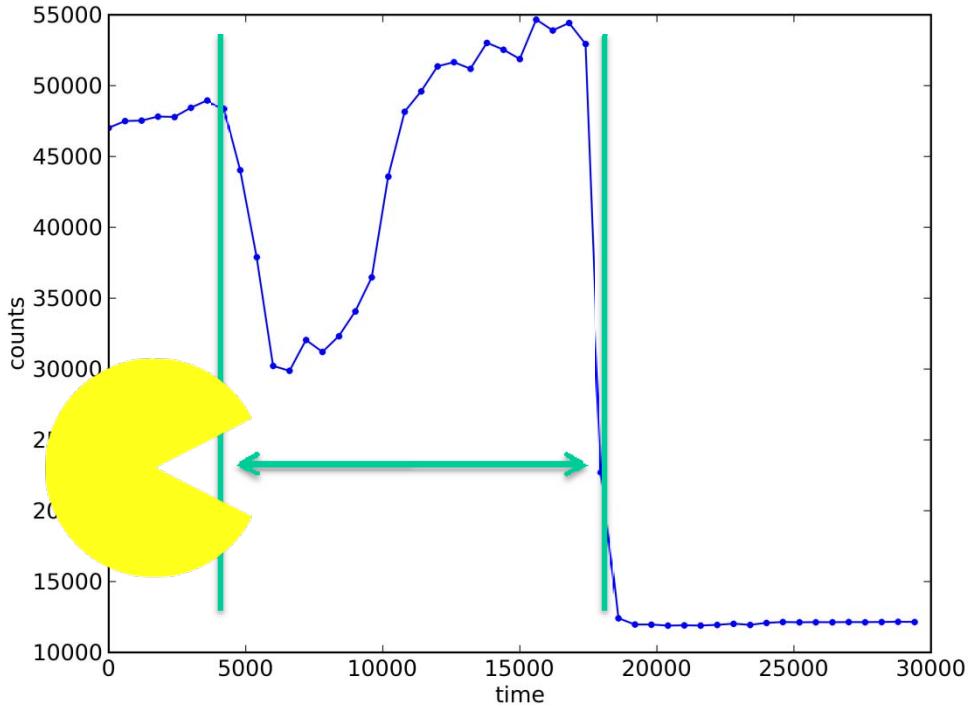


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Counts over time



Aug. 2008 intensity collection

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Reciprocal space maps of wavelength/divergence
character

Double-crystal data

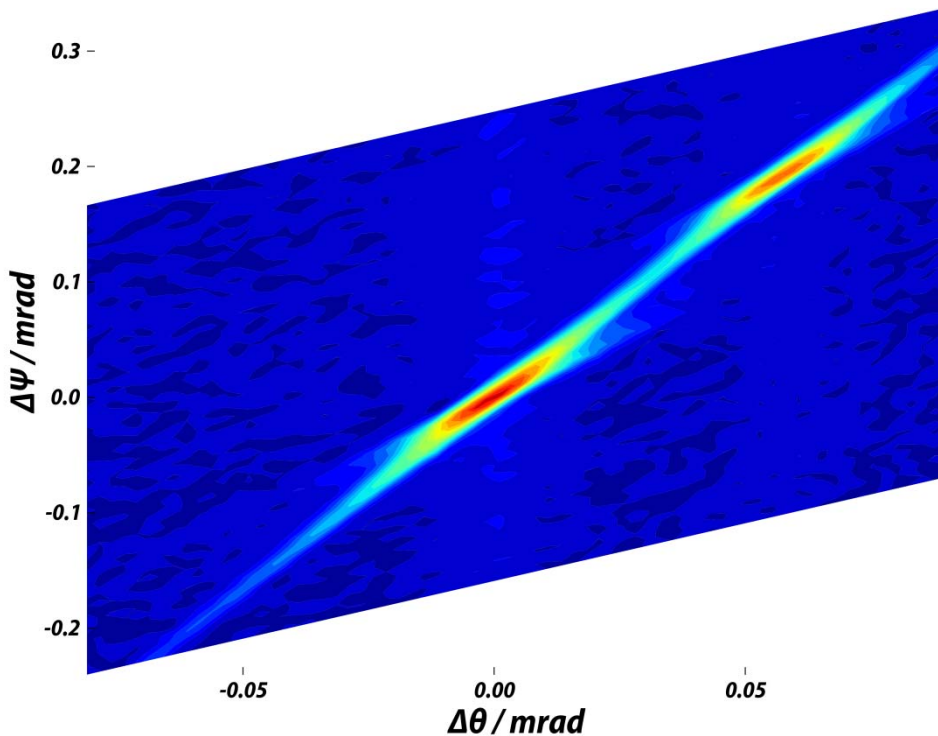
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RSM: well-aligned

$x = 9.69 \mu\text{m}; y = -24.44 \mu\text{m}; z = -148.42 \mu\text{m}; \theta = 8.21 \text{ mrad}; \varphi = 0.92 \text{ mrad}; \chi = -0.97 \text{ mrad}$



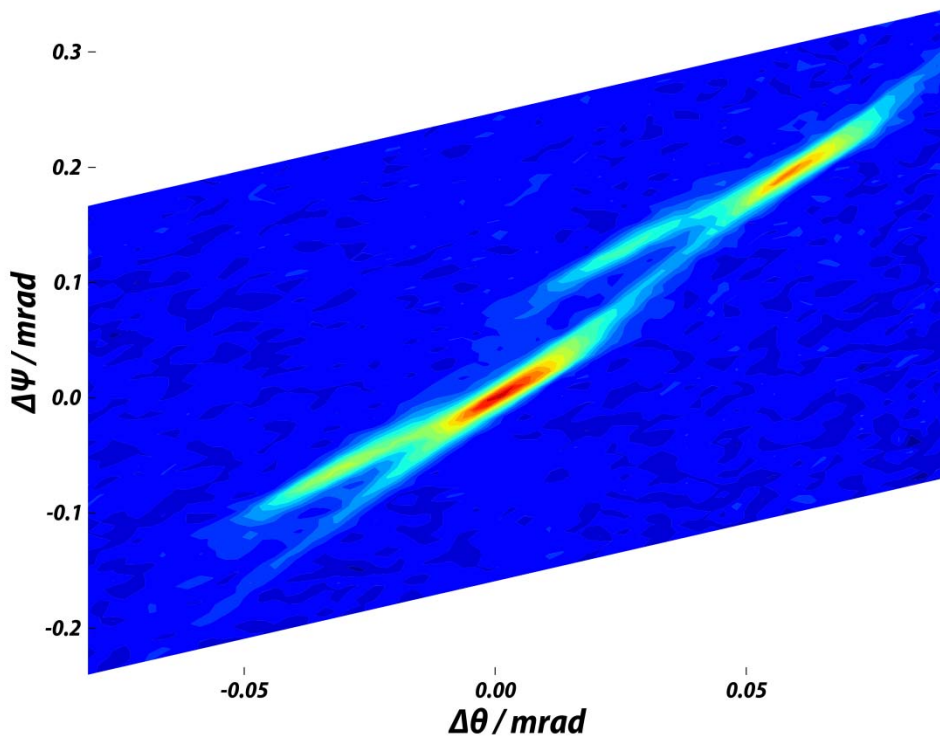
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RSM: misaligned

$x = 30.45 \mu\text{m}; y = 16.39 \mu\text{m}; z = 17.96 \mu\text{m}; \theta = 8.75 \text{ mrad}; \varphi = 0.22 \text{ mrad}; \chi = 1.29 \text{ mrad}$



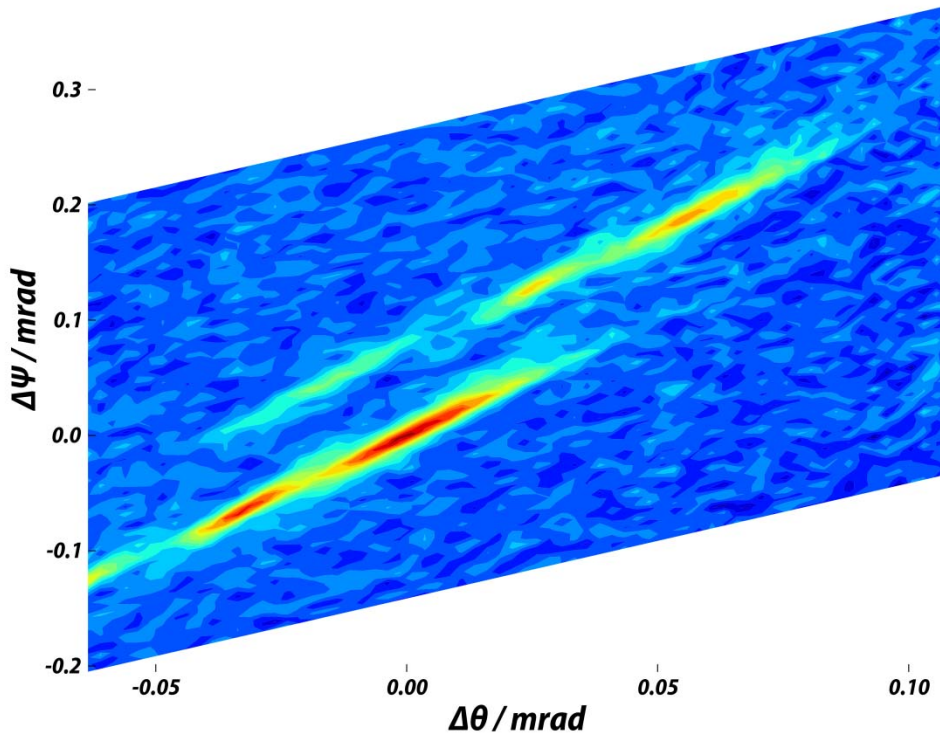
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RSM: very misaligned

$x = -7.81 \mu\text{m}; y = -38.67 \mu\text{m}; z = -35.93 \mu\text{m}; \theta = 10.91 \text{ mrad}; \varphi = 0.21 \text{ mrad}; \chi = -0.83 \text{ mrad}$



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Conclusions

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Conclusions and plans

- **Conclusions**
 - **QMC is an easy way to sample a high-dimensional alignment space**
 - **Results can reveal correlations between parameters, or drift over time**
 - **Initial collections of double-crystal data show interesting structure**
- **Future plans**
 - **Collection of representative set of RSMs**
 - **Quantitative analysis of RSMs**

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Contributions

- Donald Windover, co-leader of the XRM project, performed an initial demonstration of the instrument in 2003 and assisted in the alignment for the data presented here;
- Albert Henins designed and built the DCD, and cut the silicon channels;
- and Jim Cline, co-leader of the XRM project, developed the DCD strategy in collaboration with Dick Deslattes.

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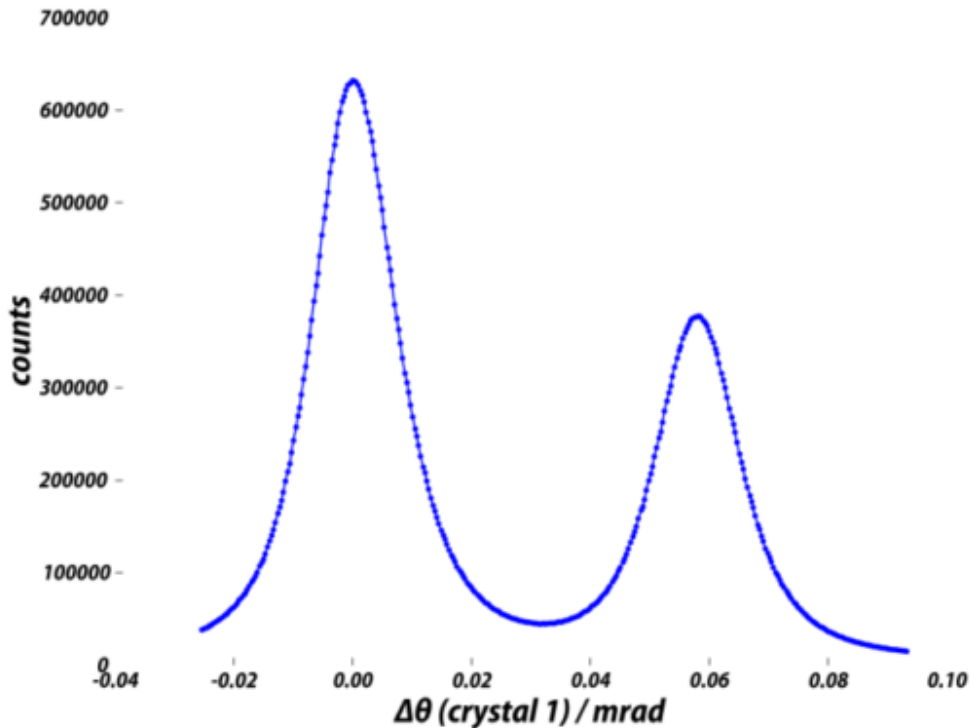
Supplemental Material

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Single crystal rocking curve of first monochromator crystal



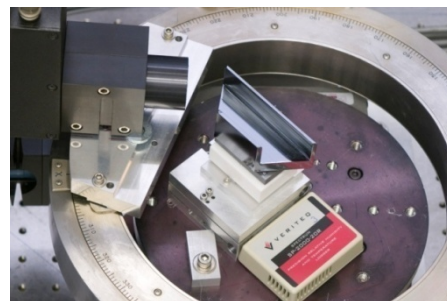
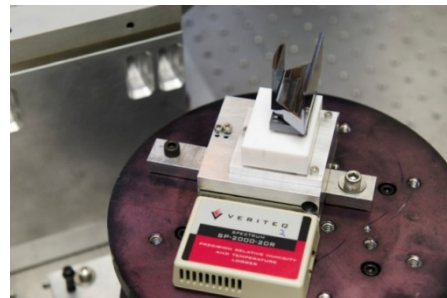
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Metrological aspects of high-resolution double crystal spectrometry

- Goniometers
 - Micro-Controle stages driven by harmonic drive steppers
 - Heidenhain 800 optical encoders
- Crystals
 - From 640d boules: d-spacing known
 - Si (440) three-bounce channels
 - High resolution, narrow tails

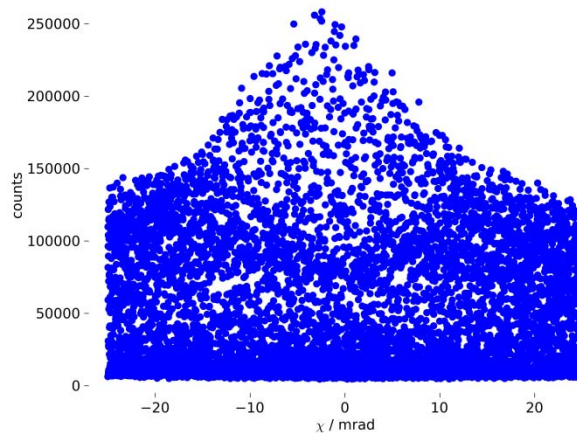
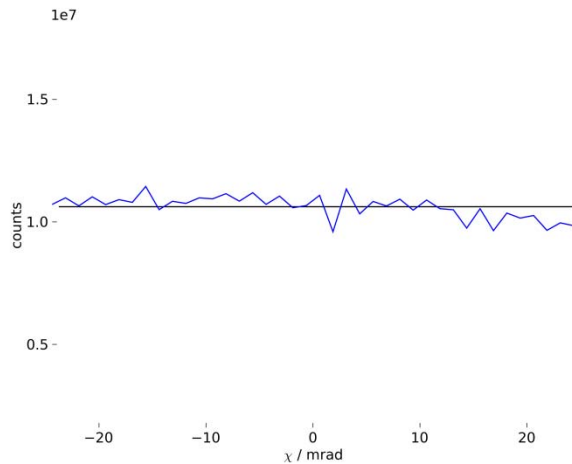


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Chi angle: scatter plot versus weighted histogram plot



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Powder diffraction SRMs planned for recertification on CDPBD

Diffraction Application	SRM Number	Composition
<i>Line Position</i>	640d	Silicon Powder
<i>Line Shape</i>	660b	LaB ₆ Powder
<i>Instrument Response</i>	1976a	Sintered Alumina Plate
<i>Quantitative Analysis</i>	676a	Alumina (corundum) Powder



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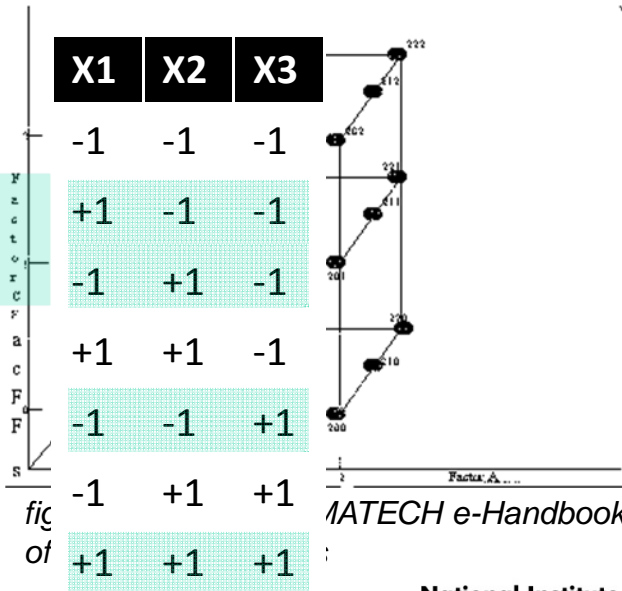


Factorial and fractional factorial experiment designs

- Factorial and fractional factorial designs
 - Effective, easy to interpret conventional statistical designs
 - Typically only used for 2, occasionally 3 levels
- Factorial designs are just multi-dimensional grids

2^3 factorial design:

$2^{(3-1)}$ fractional factorial design:



NIST e-Handbook

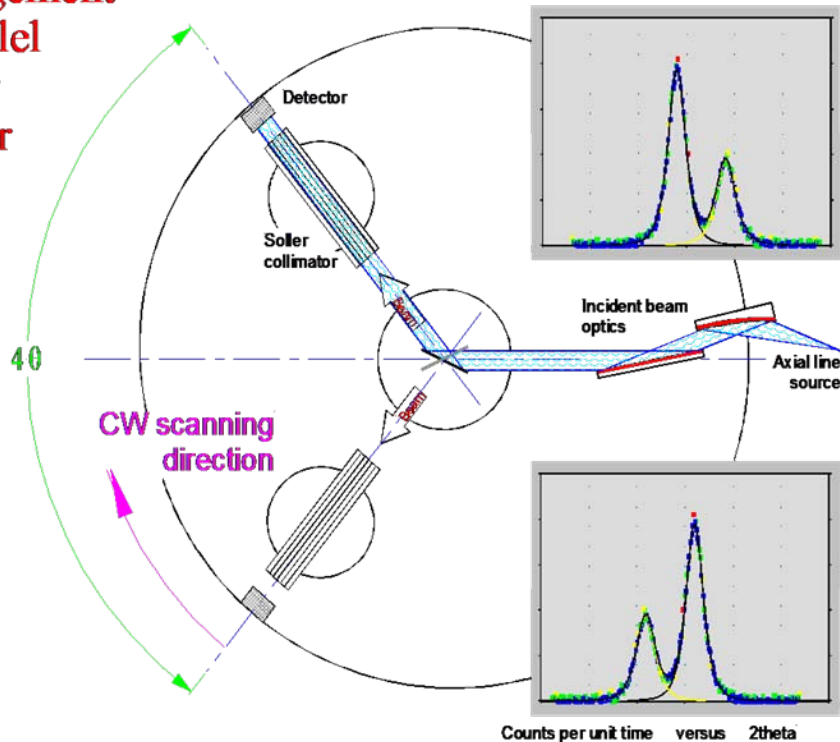
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Diagram of old NIST Parallel Beam Powder Diffractometer

Overall arrangement of NIST Parallel Beam Powder Diffractometer



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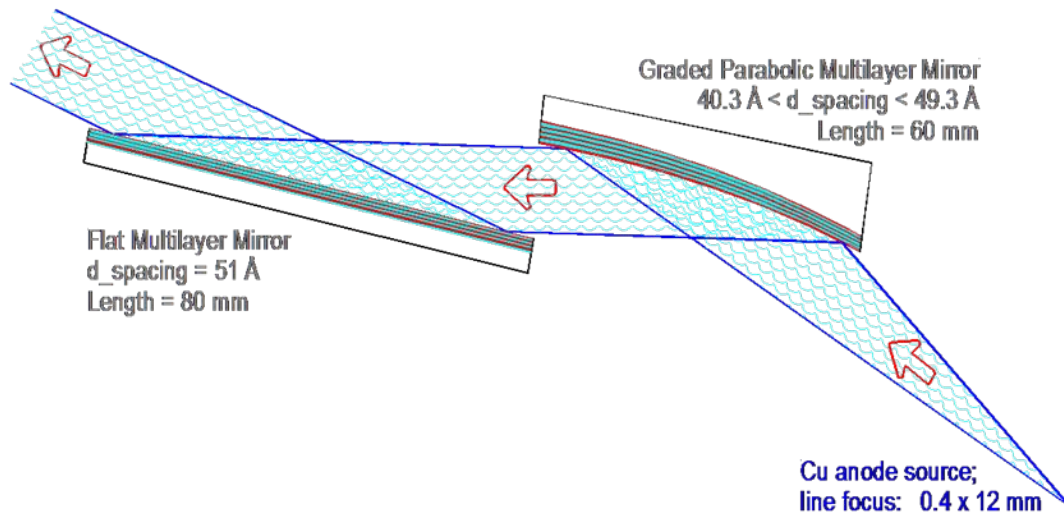
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Diagram of old NIST Parallel Beam Powder Diffractometer primary x-ray beam optics

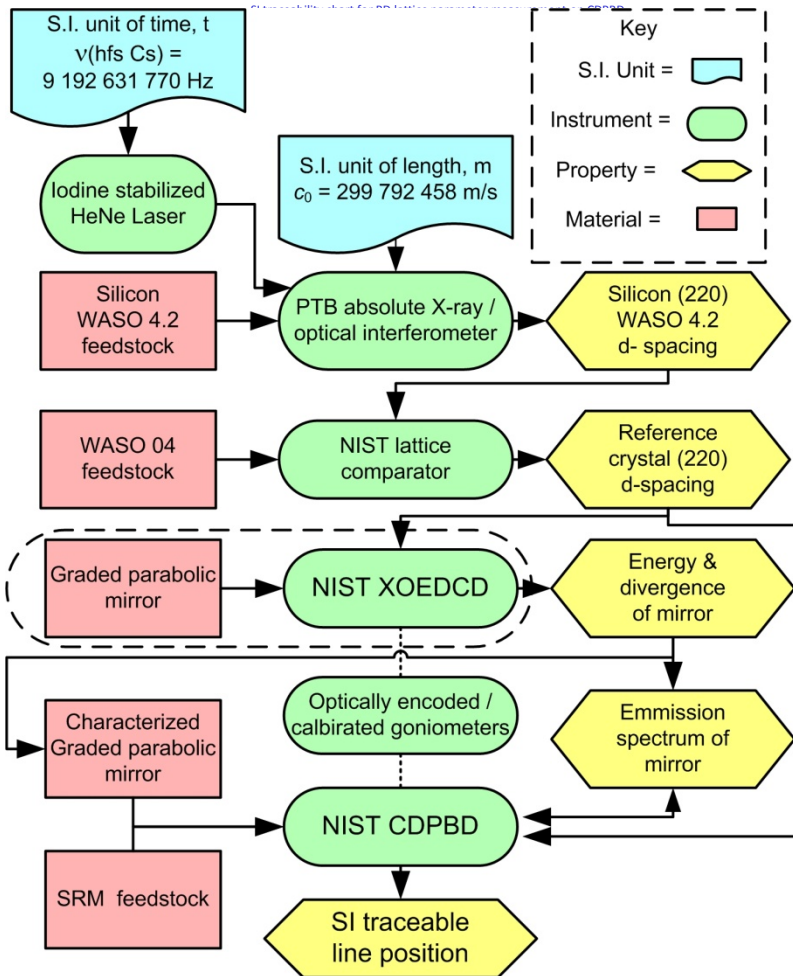
Primary X-ray Beam Optics for NIST Parallel Beam Powder Diffractometer

Cross section of parallel x-rays: about 0.7 x 15 mm
Flux = 5 GHz @ 2 kW. Energy window = 40 eV



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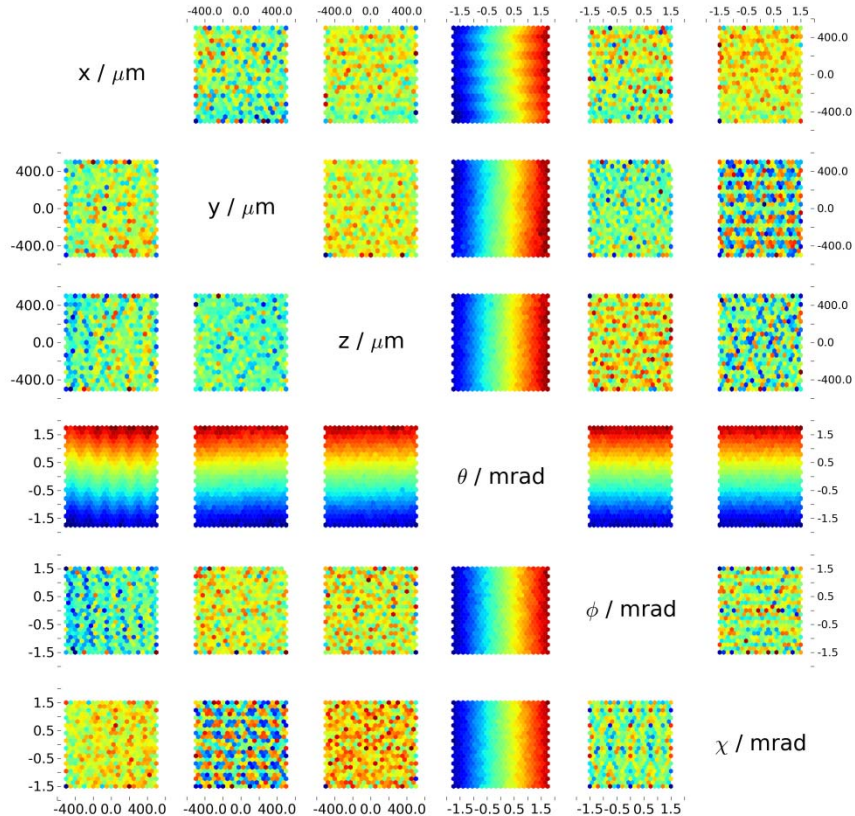


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Example autocollimator data



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NIST CDPBD

- Rigorously characterized Heidenhain 905s
- Spherical air bearing for alignment
- In AML ± 0.01 C space
- Multiple configurations
 - HRXRD
 - XRR
 - PD

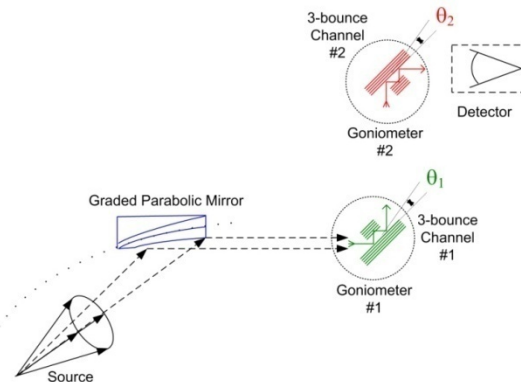
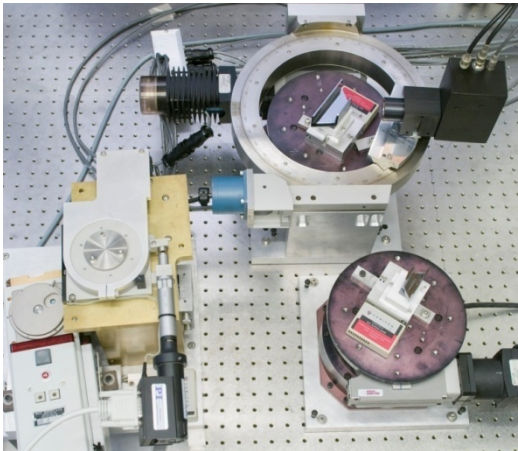


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XOEDCD, non-dispersive configuration



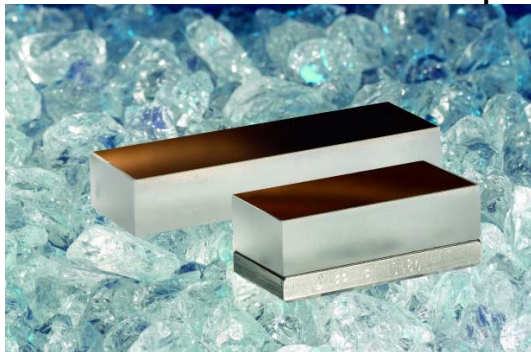
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Graded multilayer x-ray optics

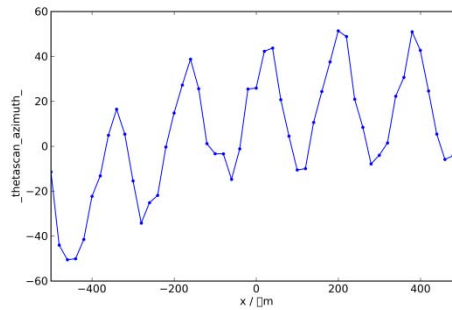
- Shaped substrates deposited with periodic multilayer of varying d-spacing for high reflectivity
- Becoming ubiquitous for laboratory x-ray instruments
- Improved source quality over other optics options
 - **Customized divergence and source size**
 - **Somewhat monochromated beam ($\Delta d/d \sim 10\%$)**
- Two-dimensional parabola for beam collimated in one axis
- Three-dimensional optics beginning to appear



Images from http://www.incoatec.de/GoebelMirrors_36.html
and <http://www.xenocs.com/range-2D-diffraction-optics.htm>

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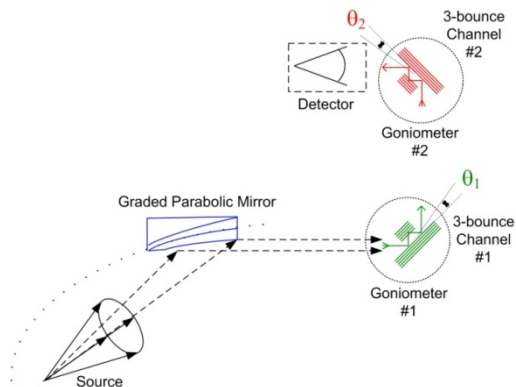
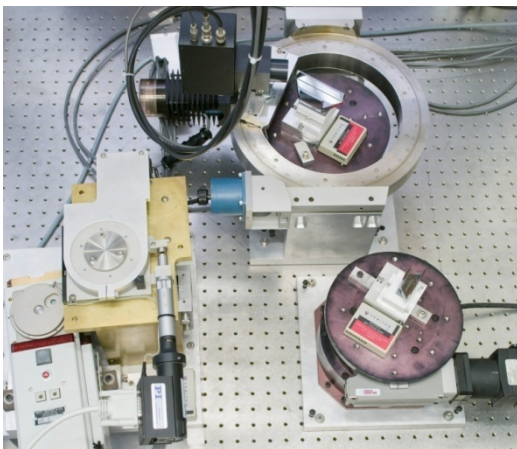


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XOEDCD, dispersive configuration



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Parabolic graded multilayer x-ray optics for powder diffraction

- Conventional powder diffraction optics: focusing
- Parabolic graded multilayers
 - **Low divergence**
 - **Higher resolution**

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Study of the variation of total reflected intensity with mirror position

- Detector placed directly in front of six-axis mirror housing
 - Source at @??
 - Attenuating foil used to bring counts down into range of detector

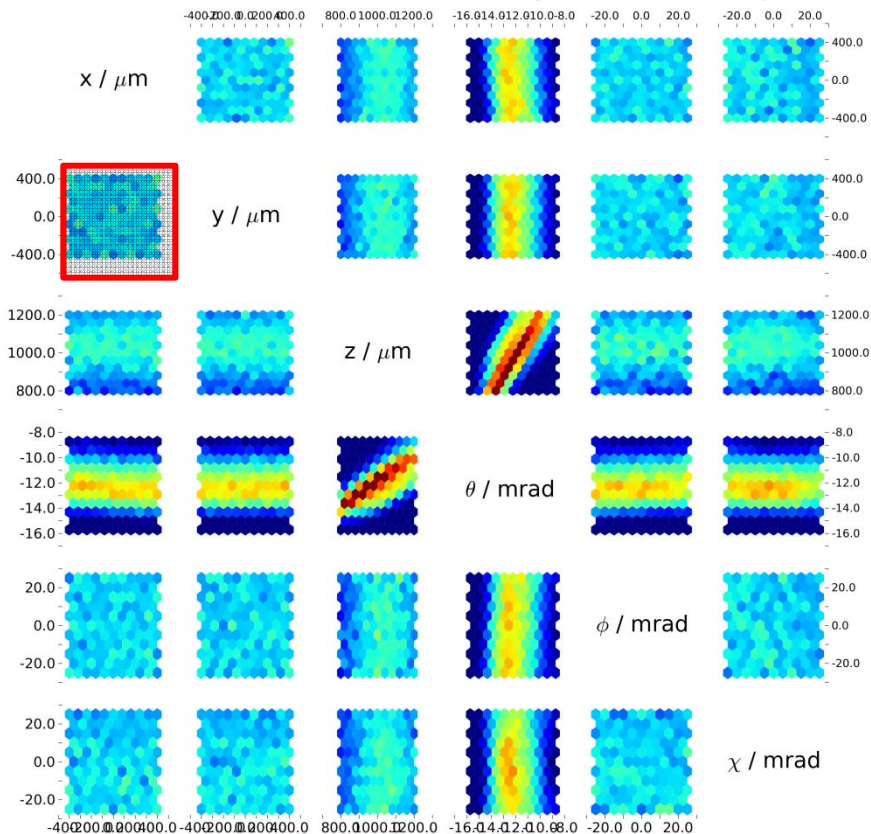
@ Picture of detector in front of mirror housing

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Two-dimensional hexagonal bin plots

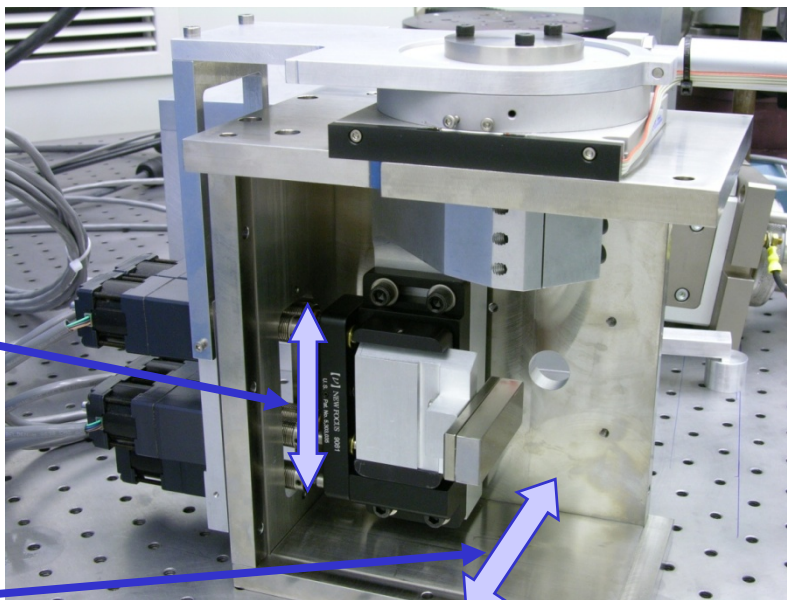


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Six-axis stage directions of motion: x position and y position



y

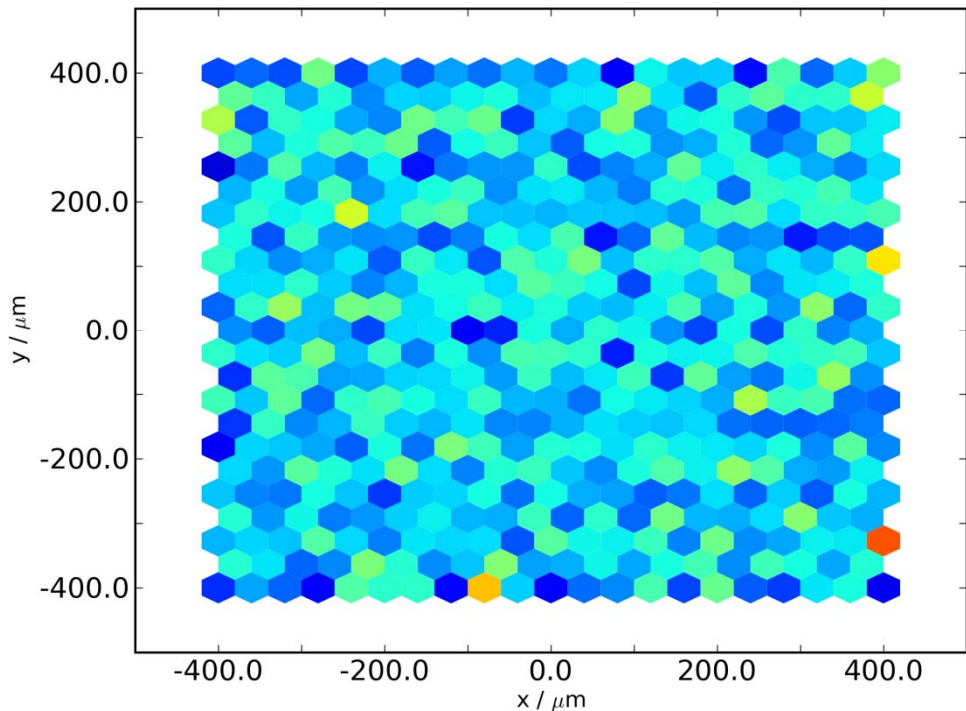
x

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x position versus y position

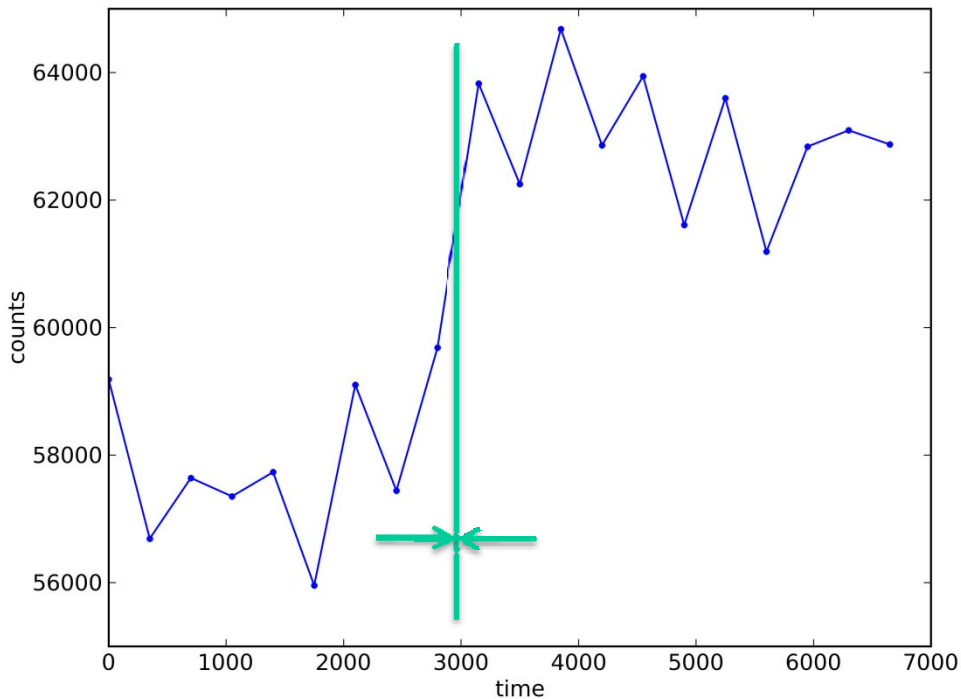


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Counts over time



Feb. 2009 intensity collection

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